

**Search Notes**

Application/Control No.

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Examiner

Chuck Huynh

Applicant(s)/Patent under  
Reexamination

PECEN ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
Updated	Search	6/7/2007	CH
455	403	6/7/2007	CH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass	6/7/2007	CH
Backward Citations	6/7/2007	CH
Combined Text Search	6/7/2007	CH